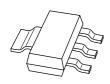
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# OT406 Four-quadrant triac, enhanced noise immunity Rev. 01 — 19 May 2008 P

**Product data sheet** 

## **Product profile**

## 1.1 General description

Passivated sensitive gate triac in a SOT223 surface-mountable plastic package

#### 1.2 Features

- Sensitive gate
- Direct interfacing to logic level ICs
- Enhanced immunity to voltage transients and noise
- Gate triggering in four quadrants
- Direct interfacing to low power gate drive circuits
- Blocking voltage to 600 V

## 1.3 Applications

- Home appliances
- Low power AC fan speed controllers
- Low power motor control
- Low power loads in industrial process control

#### 1.4 Quick reference data

- $V_{DRM} \le 600 \text{ V}$
- $I_{TSM} \le 12.5 \text{ A (t = 20 ms)}$
- $I_{T(RMS)} \le 1 A$

- $I_{GT} \le 3 \text{ mA}$
- $I_{GT} \le 5 \text{ mA } (T2-G+)$

## **Pinning information**

#### Table 1. **Pinning**

Pin	Description	Simplified outline	Graphic symbol
1	main terminal 1 (T1)		N 1
2	main terminal 2 (T2)	4	T2—T1
3	gate (G)		sym051
4	mounting base; main terminal 2 (T2)	1 2 3	
		SOT223	



## Four-quadrant triac, enhanced noise immunity

## 3. Ordering information

## Table 2. Ordering information

Type number	Package			
	Name	Description	Version	
OT406	SC-73	plastic surface-mounted package with increased heatsink; 4 leads	SOT223	

## 4. Limiting values

## Table 3. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
$V_{DRM}$	repetitive peak off-state voltage		-	600	V
$V_{RRM}$	repetitive peak reverse voltage		-	600	V
I <sub>T(RMS)</sub>	RMS on-state current	full sine wave; $T_{sp} \le 103$ °C; see Figure 4 and 5	-	1	Α
I <sub>TSM</sub>	non-repetitive peak on-state current	full sine wave; $T_j = 25$ °C prior to surge; see Figure 2 and 3			
		t = 20 ms	-	12.5	Α
		t = 16.7 ms	-	13.8	Α
l <sup>2</sup> t	I <sup>2</sup> t for fusing	t <sub>p</sub> = 10 ms	-	1.28	A <sup>2</sup> s
dl <sub>T</sub> /dt	rate of rise of on-state current	$I_{TM} = 1 \text{ A}; I_G = 20 \text{ mA};$ $dI_G/dt = 0.2 \text{ A}/\mu\text{s}$			
		T2+ G+	-	50	A/μs
		T2+ G-	-	50	A/μs
		T2- G-	-	50	A/μs
		T2- G+	-	10	A/μs
I <sub>GM</sub>	peak gate current		-	1	Α
$P_{GM}$	peak gate power		-	2	W
P <sub>G(AV)</sub>	average gate power	over any 20 ms period	-	0.1	W
T <sub>stg</sub>	storage temperature		-40	+150	°C
T <sub>j</sub>	junction temperature		-	125	°C

## Four-quadrant triac, enhanced noise immunity

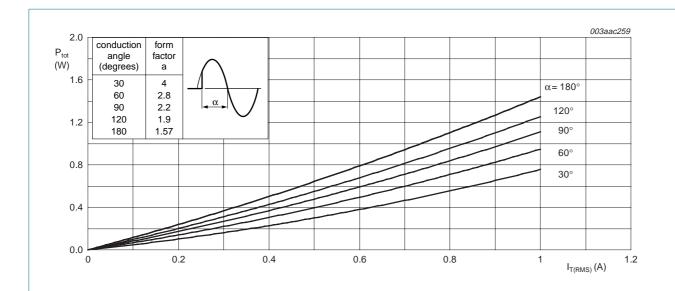


Fig 1. Total power dissipation as a function of RMS on-state current; maximum values

 $\alpha$  = conduction angle

f = 50 Hz

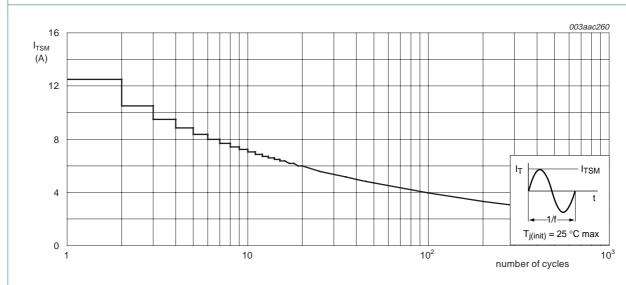
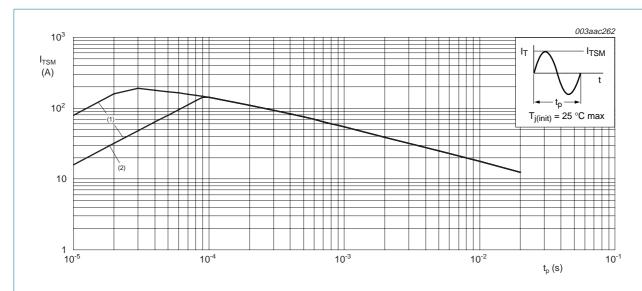


Fig 2. Non-repetitive peak on-state current as a function of the number of sinusoidal current cycles; maximum values

## Four-quadrant triac, enhanced noise immunity



 $t_p \le 20 \text{ ms}$ 

- (1) dI<sub>T</sub>/dt limit
- (2) T2- G+ quadrant limit

Fig 3. Non-repetitive peak on-state current as a function of pulse width; maximum values

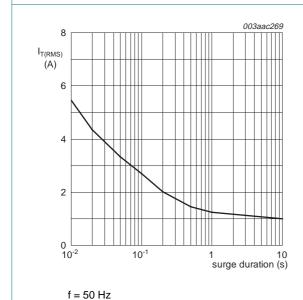


Fig 4. RMS on-state current as a function of surge duration; maximum values

 $T_{sp} = 103 \, ^{\circ}C$ 

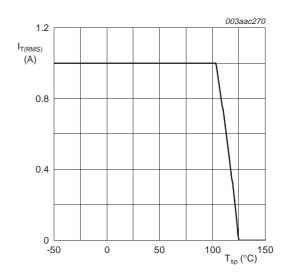


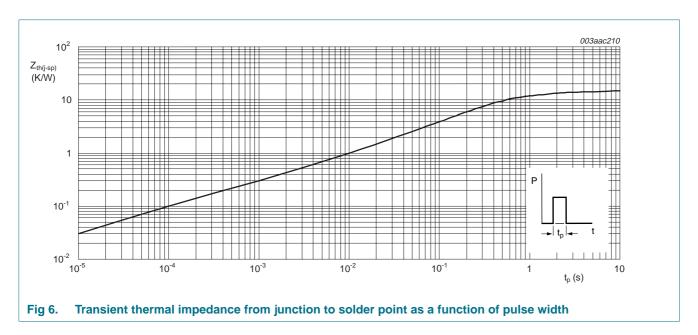
Fig 5. RMS on-state current as a function of solder point temperature; maximum values

## Four-quadrant triac, enhanced noise immunity

## 5. Thermal characteristics

Table 4. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{th(j-sp)}$	thermal resistance from junction to solder point	full cycle; see Figure 6	-	-	15	K/W
R <sub>th(j-a)</sub>		full cycle				
	ambient	for minimum footprint see Figure 13	otprint - 156 -	-	K/W	
		for pad area see <u>Figure 14</u>	-	70	-	K/W



## Four-quadrant triac, enhanced noise immunity

## 6. Static characteristics

Table 5. Static characteristics

 $T_j = 25 \,^{\circ}C$  unless otherwise specified.

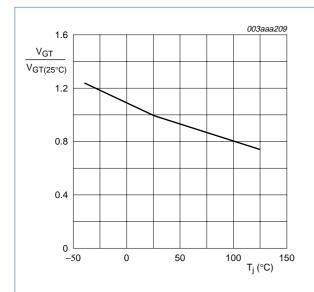
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
I <sub>GT</sub>	gate trigger current	$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; see } \frac{\text{Figure 8}}{}$				
		T2+ G+	-	-	3	mA
		T2+ G-	-	-	3	mA
		T2- G-	-	-	3	mA
		T2- G+	-	-	5	mA
I <sub>L</sub> latching current	latching current	$V_D = 12 \text{ V; } I_G = 0.1 \text{ A; see } \frac{\text{Figure 10}}{\text{ of } 100000000000000000000000000000000000$				
		T2+ G+	-	-	7	mA
		T2+ G-	-	-	20	mA
		T2- G-	-	-	7	mA
		T2- G+	-	-	7	mA
I <sub>H</sub>	holding current	$V_D = 12 \text{ V; } I_G = 0.1 \text{ A; see } \frac{\text{Figure } 11}{}$	-	-	7	mA
$V_{T}$	on-state voltage	I <sub>T</sub> = 1 A; see <u>Figure 9</u>	-	1.3	1.6	V
$V_{GT}$	gate trigger voltage	$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; see } \frac{\text{Figure 7}}{}$	-	-	1.3	V
		$V_D = V_{DRM}; I_T = 0.1 A; T_j = 125 ^{\circ}C$	0.2	-	-	V
I <sub>D</sub>	off-state current	$V_D = V_{DRM(max)}$ ; $T_j = 125  ^{\circ}C$	-	-	0.5	mA
		b branchady j				

## Four-quadrant triac, enhanced noise immunity

## 7. Dynamic characteristics

Table 6. Dynamic characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
dV <sub>D</sub> /dt	rate of rise of off-state voltage	$V_{DM} = 0.67 V_{DRM(max)}$ ; $T_j = 110 ^{\circ}\text{C}$ ; exponential waveform; gate open circuit	10	-	-	V/μs
dV <sub>com</sub> /dt	rate of change of commutating voltage	$V_{DM} = 400 \text{ V}; T_j = 110 ^{\circ}\text{C}; I_{TM} = 1 \text{ A}; \\ dI_{com}/dt = 0.44 \text{ A/ms}$	0.5	-	-	V/μs



1 003aaa205

1GT (25°C)

3 (1)
(2)
(3)
(4)

1 0

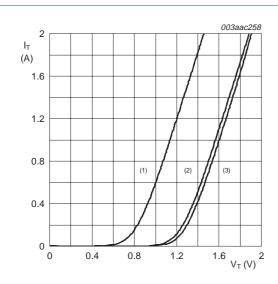
-50 0 50 100 T<sub>j</sub> (°C)

- (1) T2+ G+
- (2) T2+ G-
- (3) T2- G-
- (4) T2-G+

Fig 7. Normalized gate trigger voltage as a function of junction temperature

Fig 8. Normalized gate trigger current as a function of junction temperature

## Four-quadrant triac, enhanced noise immunity



 $V_0 = 1.254 \text{ V}; R_s = 0.31 \Omega$ 

- (1)  $T_i = 125 \,^{\circ}\text{C}$ ; typical values
- (2)  $T_j = 125 \,^{\circ}C$ ; maximum values
- (3)  $T_j = 25$  °C; maximum values

Fig 9. On-state current as a function of on-state voltage

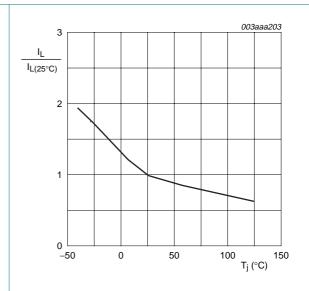


Fig 10. Normalized latching current as a function of junction temperature

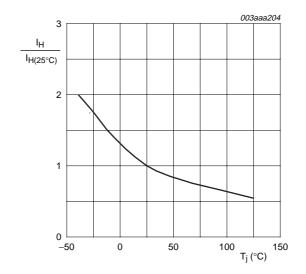


Fig 11. Normalized holding current as a function of junction temperature

## Four-quadrant triac, enhanced noise immunity

## 8. Package outline

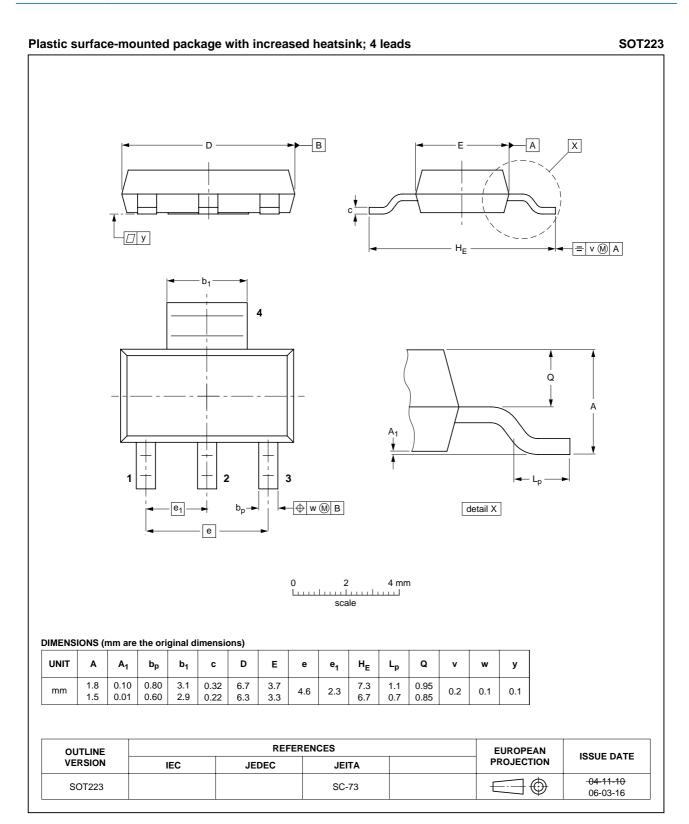


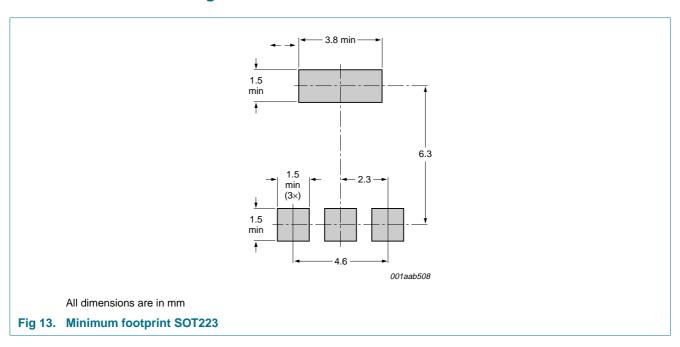
Fig 12. Package outline SOT223 (SC-73)

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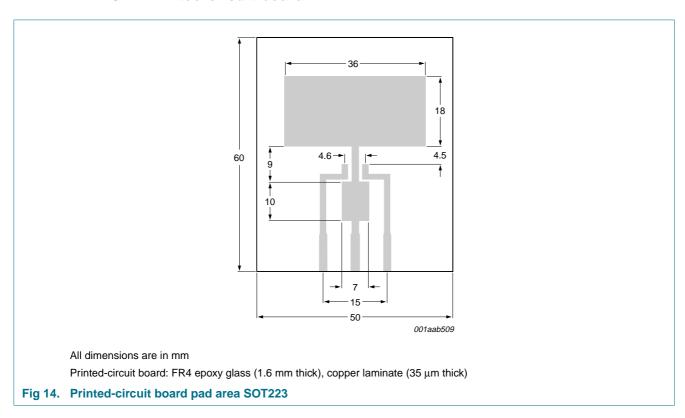
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## 9. Mounting

## 9.1 Mounting instructions



## 9.2 Printed-circuit board



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## Four-quadrant triac, enhanced noise immunity

## 10. Revision history

## Table 7. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
OT406_1	20080519	Product data sheet	-	-

#### Four-quadrant triac, enhanced noise immunity

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Document status[1][2]	Product status[3]	Definition
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Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
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## Four-quadrant triac, enhanced noise immunity

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